

<b>Notice of References Cited</b>	Application/Control No. 09/908,970	Applicant(s)/Patent Under Reexamination SEKIYA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,134,496	10-2000	Rotter et al.	701/56
	B	US-6,330,083	12-2001	Nabeshima et al.	358/474
	C	US-6,445,984	09-2002	Kellogg, David L.	701/23
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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